

Amendments to the Claims

1. (*Currently Amended*) An electric device (~~100~~) with a body (~~102~~) having a resistor (~~107~~) comprising

a phase change material being changeable between a first phase and a second phase, the resistor (~~107~~) having a first electrical resistance when the phase change material is in the first phase, and

a second electrical resistance, different from the first electrical resistance, when the phase change material is in the second phase, the phase change material constituting a conductive path between a first contact area and a second contact area, a cross-section of the conductive path being smaller than the first contact area and the second contact area.

2. (*Currently Amended*) An electric device (~~100~~) as claimed in Claim 1, wherein a part of the conductive path having said cross-section constitutes a volume of phase change material, the volume having an electrical resistance which is larger than an electrical contact resistance at the first contact area ~~and/or~~ or at the second contact area, independent of whether the phase change material is in the first phase or the second phase.

3. (*Currently Amended*) An electric device (~~100~~) as claimed in Claim 1, further comprising a heating element (~~106~~) able to conduct an electric current for enabling a transition from the first phase to the second phase.

4. (*Currently Amended*) An electric device (~~100~~) as claimed in Claim 3, wherein the heating element (~~106~~) is arranged in parallel with the resistor (~~107~~).

5. (*Currently Amended*) An electric device (~~100~~) as claimed in Claim 4, wherein the heating element (~~106~~) has a heating elements electrical resistance which is smaller than the first electrical resistance and the second electrical resistance.

6. (*Currently Amended*) An electric device (~~100~~) as claimed in Claim 5, wherein the heating elements electrical resistance is larger than 0.3 times the minimum of the first electrical resistance and the second electrical resistance.

7. (*Currently Amended*) An electric device (~~100~~) as claimed in Claim 3, wherein the heating element (~~106~~) is in direct contact with the resistor (~~107~~).

8. (*Currently Amended*) An electric device (~~100~~) as claimed in Claim 1, wherein the resistor (~~107~~) constitutes a memory element (~~170~~), and the body (~~102~~) comprises:
[[-]] an array of memory cells, each memory cell comprising a respective memory element (~~170~~) and a respective selection device (~~171~~), and
[[-]] a grid of selection lines (~~120, 121~~), each memory cell being individually accessible via the respective selection lines (~~120, 121~~) connected to the respective selection device (~~171~~).

9. (*Currently Amended*) An electric device (~~100~~) as claimed in Claim 8, wherein:
[[-]] the selection device (~~171~~) comprises a metal oxide semiconductor field effect transistor having a source region (~~172~~), a drain region (~~173~~) and a gate region (~~174~~), and
[[-]] the grid of selection lines (~~120, 121~~) comprises N first selection lines (~~120~~), M second selection lines (~~121~~), and an output line,

the resistor (~~107~~) of each memory element (~~170~~) electrically connecting a first region selected from the source region (~~172~~) and the drain region (~~173~~) of the corresponding metal oxide semiconductor field effect transistor to the output line, a second region of the corresponding metal oxide semiconductor field effect transistor selected from the source region (~~172~~) and the drain region (~~173~~) and being free from contact with the first region, being electrically connected to one of the N first selection lines (~~120~~), the gate region (~~174~~) being electrically connected to one of the M second selection lines (~~121~~).

10. (*Currently Amended*) Method of manufacturing an electric device (~~100~~) as claimed in Claim 1, comprising the steps of:

[[-]] providing a main surface of a pre-fabricated electric device (~~100~~) with a layer (107) of the phase change material, and

[[-]] reducing a cross-section of a conductive path in the layer (~~107~~) between a first contact area and a second contact area, the cross-section being smaller than the first contact area and the second contact area.

11. (*Original*) A method as claimed in Claim 10, wherein the main surface has a step profile and the step of reducing the cross-section comprises an anisotropic etching step for forming a sidewall spacer along at least a part of the step profile.

12. (*Currently Amended*) A method as claimed in Claim 10, wherein a part of the conductive path having said cross-section constitutes a volume of phase change material, and the step of reducing the cross-section comprises the sub-steps of:

[[-]] providing a resist layer sensitive to electrons,

[[-]] writing a pattern with an electron beam into the resist layer, the pattern defining at least the volume of the phase change material, and

[[-]] developing the resist.